

Action = Pattern Data * Timing Data (Limited by TimeSet) * Waveset * Drive

FIG._1

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FIG._2

n

Module

Module Test Site n Loadboard

DUT

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298-

SYSTEM

281

292

Key

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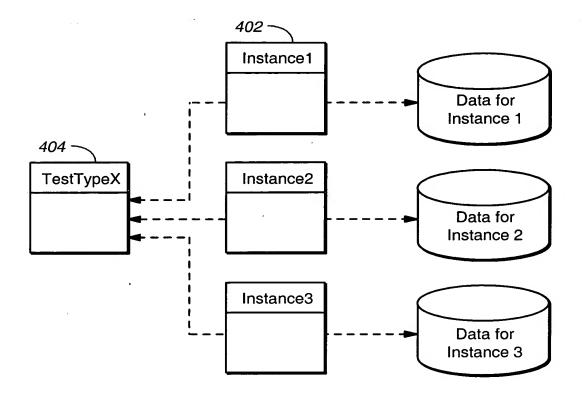
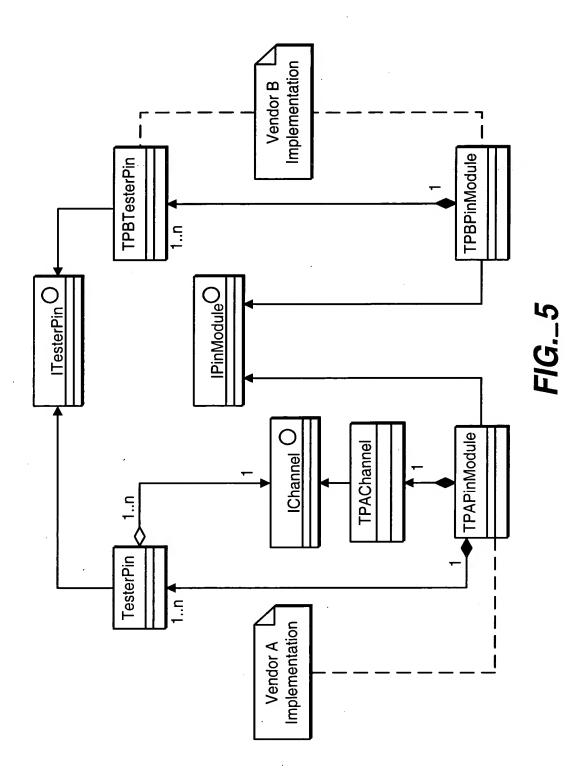


FIG._4

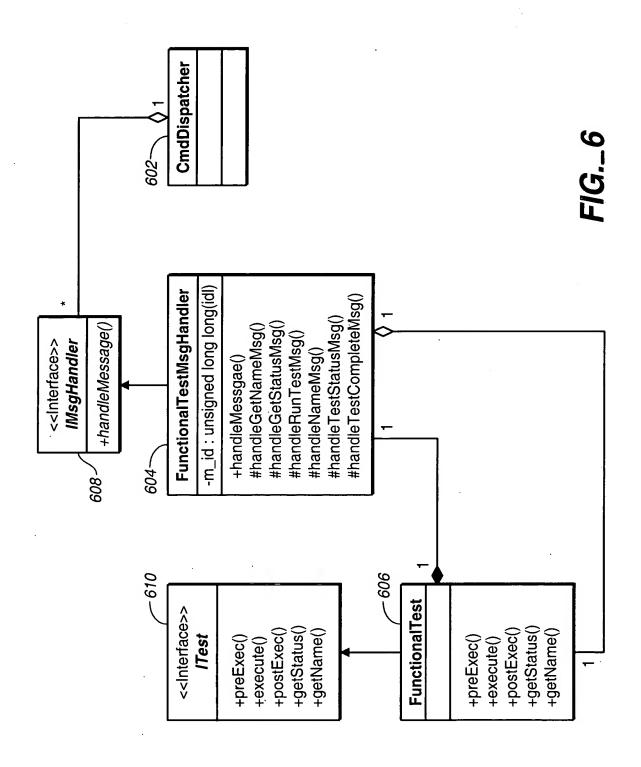
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+handleMessage()

712

- 714

<<Interface>> IMsgHandler

<<Interface>>

IDispatch

<<Application</ti>

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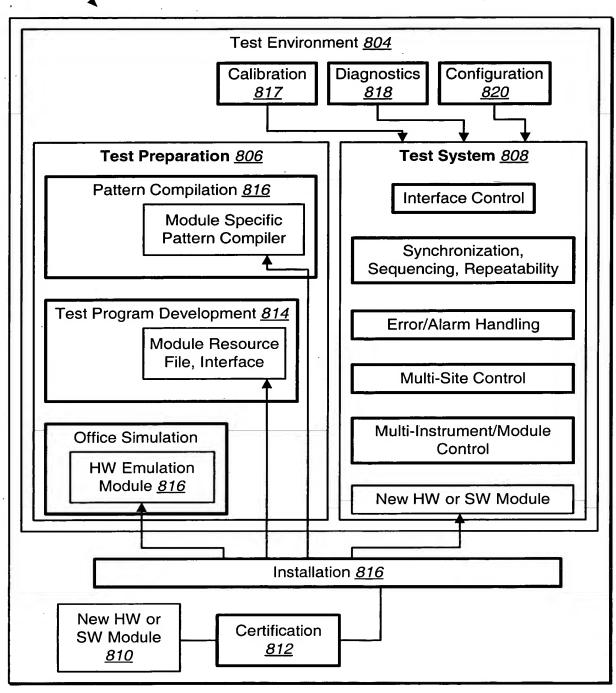


FIG._8